## Notice of References Cited

Application/Control No. 10/044,098

Applicant(s)/Patent Under Reexamination DECKER, RONALD E.

Examiner

Hanh V. Tran

Art Unit 3637

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## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,089,585	07-2000	Theobald, Markus	280/276
	В	US-5,358,265	10-1994	Yaple, Winfred E.	280/293
	. <b>C</b>	US-4,457,492	07-1984	Lahti, Terry L.	254/114
	D	US-2,655,412	10-1953	Jones	254/2B
	E	US-1,602,275	10-1926	Longstreth	254/114
	F	US-			
	G	US-			
	Н	US-		·	
	1	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	2647772	12-1990	France	Wilhelm	254/131
	0					
	Р					
	σ					
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

	TOTAL							
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
	U							
	v							
	w							
	x							

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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